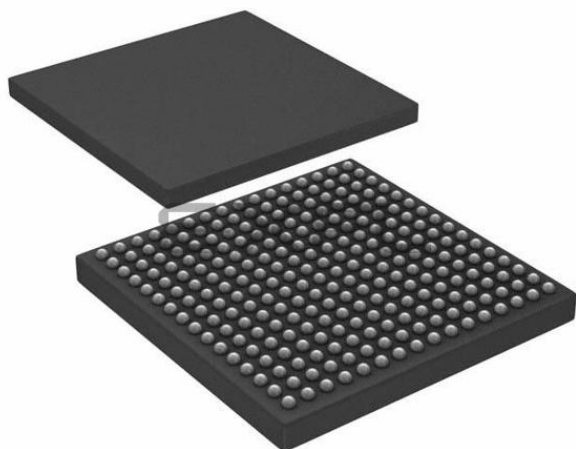




Welcome to [E-XFL.COM](https://www.e-xfl.com)

Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	2880
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	228
Number of Gates	48000
Voltage - Supply	2.25V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	256-BFCQFP with Tie Bar
Supplier Device Package	256-CQFP (75x75)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx32a-1cq256m

Table of Contents

General Description

Introduction	1-1
SX-A Family Architecture	1-1
Other Architectural Features	1-7
Programming	1-13
Related Documents	1-14
Pin Description	1-15

Detailed Specifications

Operating Conditions	2-1
Typical SX-A Standby Current	2-1
Electrical Specifications	2-2
PCI Compliance for the SX-A Family	2-3
Thermal Characteristics	2-11
SX-A Timing Model	2-14
Sample Path Calculations	2-14
Output Buffer Delays	2-15
AC Test Loads	2-15
Input Buffer Delays	2-16
C-Cell Delays	2-16
Cell Timing Characteristics	2-16
Timing Characteristics	2-17
Temperature and Voltage Derating Factors	2-17
Timing Characteristics	2-18

Package Pin Assignments

208-Pin PQFP	3-1
100-Pin TQFP	3-5
144-Pin TQFP	3-8
176-Pin TQFP	3-11
329-Pin PBGA	3-14
144-Pin FBGA	3-18
256-Pin FBGA	3-21
484-Pin FBGA	3-26

Datasheet Information

List of Changes	4-1
Datasheet Categories	4-3
International Traffic in Arms Regulations (ITAR) and Export Administration Regulations (EAR)	4-3

General Description

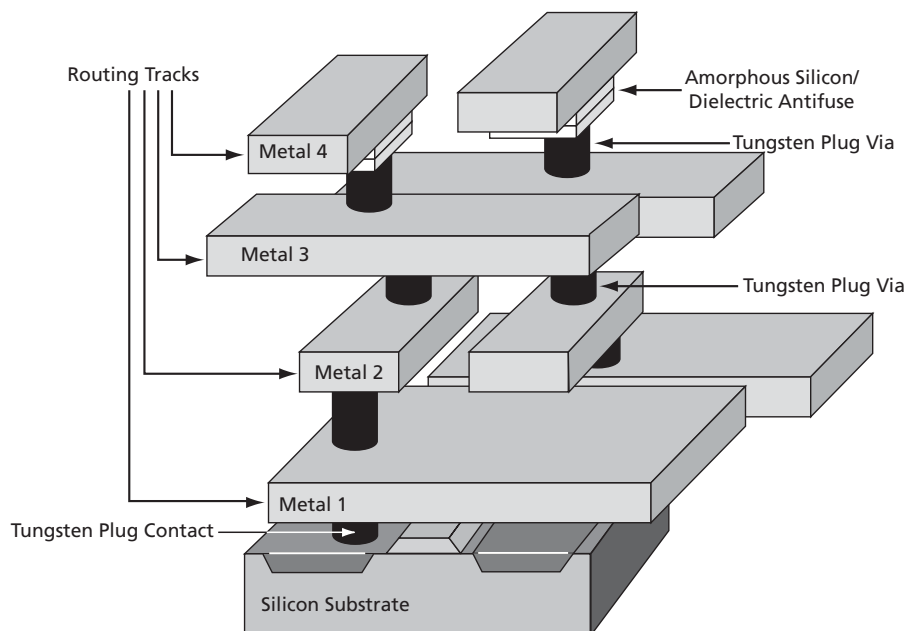
Introduction

The Actel SX-A family of FPGAs offers a cost-effective, single-chip solution for low-power, high-performance designs. Fabricated on 0.22 μm / 0.25 μm CMOS antifuse technology and with the support of 2.5 V, 3.3 V and 5 V I/Os, the SX-A is a versatile platform to integrate designs while significantly reducing time-to-market.

SX-A Family Architecture

The SX-A family's device architecture provides a unique approach to module organization and chip routing that satisfies performance requirements and delivers the most optimal register/logic mix for a wide variety of applications.

Interconnection between these logic modules is achieved using Actel's patented metal-to-metal programmable antifuse interconnect elements ([Figure 1-1](#)). The antifuses are normally open circuit and, when programmed, form a permanent low-impedance connection.



Note: The A54SX72A device has four layers of metal with the antifuse between Metal 3 and Metal 4. The A54SX08A, A54SX16A, and A54SX32A devices have three layers of metal with the antifuse between Metal 2 and Metal 3.

Figure 1-1 • SX-A Family Interconnect Elements

Boundary-Scan Testing (BST)

All SX-A devices are IEEE 1149.1 compliant and offer superior diagnostic and testing capabilities by providing Boundary Scan Testing (BST) and probing capabilities. The BST function is controlled through the special JTAG pins (TMS, TDI, TCK, TDO, and TRST). The functionality of the JTAG pins is defined by two available modes: Dedicated and Flexible. TMS cannot be employed as a user I/O in either mode.

Dedicated Mode

In Dedicated mode, all JTAG pins are reserved for BST; designers cannot use them as regular I/Os. An internal pull-up resistor is automatically enabled on both TMS and TDI pins, and the TMS pin will function as defined in the IEEE 1149.1 (JTAG) specification.

To select Dedicated mode, the user must reserve the JTAG pins in Actel's Designer software. Reserve the JTAG pins by checking the **Reserve JTAG** box in the Device Selection Wizard (Figure 1-12).

The default for the software is Flexible mode; all boxes are unchecked. Table 1-5 lists the definitions of the options in the Device Selection Wizard.



Figure 1-12 • Device Selection Wizard

Table 1-5 • Reserve Pin Definitions

Pin	Function
Reserve JTAG	Keeps pins from being used and changes the behavior of JTAG pins (no pull-up on TMS)
Reserve JTAG Test Reset	Regular I/O or JTAG reset with an internal pull-up
Reserve Probe	Keeps pins from being used or regular I/O

Flexible Mode

In Flexible mode, TDI, TCK, and TDO may be employed as either user I/Os or as JTAG input pins. The internal resistors on the TMS and TDI pins are not present in flexible JTAG mode.

To select the Flexible mode, uncheck the **Reserve JTAG** box in the Device Selection Wizard dialog in the Actel Designer software. In Flexible mode, TDI, TCK, and TDO pins may function as user I/Os or BST pins. The functionality is controlled by the BST Test Access Port (TAP) controller. The TAP controller receives two control inputs, TMS and TCK. Upon power-up, the TAP controller enters the Test-Logic-Reset state. In this state, TDI, TCK, and TDO function as user I/Os. The TDI, TCK, and TDO are transformed from user I/Os into BST pins when a rising edge on TCK is detected while TMS is at logic low. To return to Test-Logic Reset state, TMS must be high for at least five TCK cycles. **An external 10 k pull-up resistor to V_{CC} should be placed on the TMS pin to pull it High by default.**

Table 1-6 describes the different configuration requirements of BST pins and their functionality in different modes.

Table 1-6 • Boundary-Scan Pin Configurations and Functions

Mode	Designer "Reserve JTAG" Selection	TAP Controller State
Dedicated (JTAG)	Checked	Any
Flexible (User I/O)	Unchecked	Test-Logic-Reset
Flexible (JTAG)	Unchecked	Any EXCEPT Test-Logic-Reset

TRST Pin

The TRST pin functions as a dedicated Boundary-Scan Reset pin when the **Reserve JTAG Test Reset** option is selected as shown in Figure 1-12. An internal pull-up resistor is permanently enabled on the TRST pin in this mode. Actel recommends connecting this pin to ground in normal operation to keep the JTAG state controller in the Test-Logic-Reset state. When JTAG is being used, it can be left floating or can be driven high.

When the **Reserve JTAG Test Reset** option is not selected, this pin will function as a regular I/O. If unused as an I/O in the design, it will be configured as a tristated output.

Probing Capabilities

SX-A devices also provide an internal probing capability that is accessed with the JTAG pins. The Silicon Explorer II diagnostic hardware is used to control the TDI, TCK, TMS, and TDO pins to select the desired nets for debugging. The user assigns the selected internal nets in Actel Silicon Explorer II software to the PRA/PRB output pins for observation. Silicon Explorer II automatically places the device into JTAG mode. However, probing functionality is only activated when the TRST pin is driven high or left floating, allowing the internal pull-up resistor to pull TRST High. If the TRST pin is held Low, the TAP controller remains in the Test-Logic-Reset state so no probing can be performed. However, the user must drive the TRST pin High or allow the internal pull-up resistor to pull TRST High.

When selecting the **Reserve Probe Pin** box as shown in [Figure 1-12 on page 1-9](#), direct the layout tool to reserve the PRA and PRB pins as dedicated outputs for probing. This **Reserve** option is merely a guideline. If the designer assigns user I/Os to the PRA and PRB pins and selects the **Reserve Probe Pin** option, Designer Layout will override the **Reserve Probe Pin** option and place the user I/Os on those pins.

To allow probing capabilities, the security fuse must not be programmed. Programming the security fuse disables the JTAG and probe circuitry. [Table 1-9](#) summarizes the possible device configurations for probing once the device leaves the Test-Logic-Reset JTAG state.

Table 1-9 • Device Configuration Options for Probe Capability (TRST Pin Reserved)

JTAG Mode	TRST ¹	Security Fuse Programmed	PRA, PRB ²	TDI, TCK, TDO ²
Dedicated	Low	No	User I/O ³	JTAG Disabled
	High	No	Probe Circuit Outputs	JTAG I/O
Flexible	Low	No	User I/O ³	User I/O ³
	High	No	Probe Circuit Outputs	JTAG I/O
		Yes	Probe Circuit Secured	Probe Circuit Secured

Notes:

1. If the TRST pin is not reserved, the device behaves according to TRST = High as described in the table.
2. Avoid using the TDI, TCK, TDO, PRA, and PRB pins as input or bidirectional ports. Since these pins are active during probing, input signals will not pass through these pins and may cause contention.
3. If no user signal is assigned to these pins, they will behave as unused I/Os in this mode. Unused pins are automatically tristated by the Designer software.

Detailed Specifications

Operating Conditions

Table 2-1 • Absolute Maximum Ratings

Symbol	Parameter	Limits	Units
V_{CCI}	DC Supply Voltage for I/Os	−0.3 to +6.0	V
V_{CCA}	DC Supply Voltage for Arrays	−0.3 to +3.0	V
V_I	Input Voltage	−0.5 to +5.75	V
V_O	Output Voltage	−0.5 to $+V_{CCI} + 0.5$	V
T_{STG}	Storage Temperature	−65 to +150	°C

Note: *Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. Exposure to absolute maximum rated conditions for extended periods may affect device reliability. Devices should not be operated outside the "Recommended Operating Conditions".

Table 2-2 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Units
Temperature Range	0 to +70	−40 to +85	°C
2.5 V Power Supply Range (V_{CCA} and V_{CCI})	2.25 to 2.75	2.25 to 2.75	V
3.3 V Power Supply Range (V_{CCI})	3.0 to 3.6	3.0 to 3.6	V
5 V Power Supply Range (V_{CCI})	4.75 to 5.25	4.75 to 5.25	V

Typical SX-A Standby Current

Table 2-3 • Typical Standby Current for SX-A at 25°C with $V_{CCA} = 2.5$ V

Product	$V_{CCI} = 2.5$ V	$V_{CCI} = 3.3$ V	$V_{CCI} = 5$ V
A54SX08A	0.8 mA	1.0 mA	2.9 mA
A54SX16A	0.8 mA	1.0 mA	2.9 mA
A54SX32A	0.9 mA	1.0 mA	3.0 mA
A54SX72A	3.6 mA	3.8 mA	4.5 mA

Table 2-4 • Supply Voltages

V_{CCA}	V_{CCI}^*	Maximum Input Tolerance	Maximum Output Drive
2.5 V	2.5 V	5.75 V	2.7 V
2.5 V	3.3 V	5.75 V	3.6 V
2.5 V	5 V	5.75 V	5.25 V

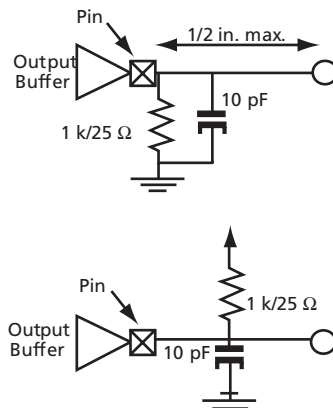
Note: *3.3 V PCI is not 5 V tolerant due to the clamp diode, but instead is 3.3 V tolerant.

Table 2-10 • AC Specifications (3.3 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \leq 0.3V_{CCI}^1$	$-12V_{CCI}$	–	mA
		$0.3V_{CCI} \leq V_{OUT} < 0.9V_{CCI}^1$	$(-17.1(V_{CCI} - V_{OUT}))$	–	mA
		$0.7V_{CCI} < V_{OUT} < V_{CCI}^{1,2}$	–	EQ 2-3 on page 2-7	–
	(Test Point)	$V_{OUT} = 0.7V_{CC}^2$	–	$-32V_{CCI}$	mA
$I_{OL(AC)}$	Switching Current Low	$V_{CCI} > V_{OUT} \geq 0.6V_{CCI}^1$	$16V_{CCI}$	–	mA
		$0.6V_{CCI} > V_{OUT} > 0.1V_{CCI}^1$	$(26.7V_{OUT})$	–	mA
		$0.18V_{CCI} > V_{OUT} > 0^{1,2}$	–	EQ 2-4 on page 2-7	–
	(Test Point)	$V_{OUT} = 0.18V_{CC}^2$	–	$38V_{CCI}$	mA
I_{CL}	Low Clamp Current	$-3 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1)/0.015$	–	mA
I_{CH}	High Clamp Current	$V_{CCI} + 4 > V_{IN} \geq V_{CCI} + 1$	$25 + (V_{IN} - V_{CCI} - 1)/0.015$	–	mA
$slew_R$	Output Rise Slew Rate	$0.2V_{CCI} - 0.6V_{CCI}$ load ³	1	4	V/ns
$slew_F$	Output Fall Slew Rate	$0.6V_{CCI} - 0.2V_{CCI}$ load ³	1	4	V/ns

Notes:

1. Refer to the V/I curves in Figure 2-2 on page 2-7. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.
2. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (C and D) are provided with the respective diagrams in Figure 2-2 on page 2-7. The equation defined maximum should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.
3. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per the latest revision of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is required (the maximum is no longer simply a guideline). Rise slew rate does not apply to open drain outputs.



Thermal Characteristics

Introduction

The temperature variable in Actel Designer software refers to the junction temperature, not the ambient, case, or board temperatures. This is an important distinction because dynamic and static power consumption will cause the chip's junction to be higher than the ambient, case, or board temperatures. EQ 2-9 and EQ 2-10 give the relationship between thermal resistance, temperature gradient and power.

$$\theta_{JA} = \frac{T_J - T_A}{P}$$

EQ 2-9

$$\theta_{JA} = \frac{T_C - T_A}{P}$$

EQ 2-10

Where:

- θ_{JA} = Junction-to-air thermal resistance
- θ_{JC} = Junction-to-case thermal resistance
- T_J = Junction temperature
- T_A = Ambient temperature
- T_C = Ambient temperature
- P = total power dissipated by the device

Table 2-12 • Package Thermal Characteristics

Package Type	Pin Count	θ_{JC}	θ_{JA}			Units
			Still Air	1.0 m/s 200 ft./min.	2.5 m/s 500 ft./min.	
Thin Quad Flat Pack (TQFP)	100	14	33.5	27.4	25	°C/W
Thin Quad Flat Pack (TQFP)	144	11	33.5	28	25.7	°C/W
Thin Quad Flat Pack (TQFP)	176	11	24.7	19.9	18	°C/W
Plastic Quad Flat Pack (PQFP) ¹	208	8	26.1	22.5	20.8	°C/W
Plastic Quad Flat Pack (PQFP) with Heat Spreader ²	208	3.8	16.2	13.3	11.9	°C/W
Plastic Ball Grid Array (PBGA)	329	3	17.1	13.8	12.8	°C/W
Fine Pitch Ball Grid Array (FBGA)	144	3.8	26.9	22.9	21.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	256	3.8	26.6	22.8	21.5	°C/W
Fine Pitch Ball Grid Array (FBGA)	484	3.2	18	14.7	13.6	°C/W

Notes:

- The A54SX08A PQ208 has no heat spreader.
- The SX-A PQ208 package has a heat spreader for A54SX16A, A54SX32A, and A54SX72A.

Timing Characteristics

Timing characteristics for SX-A devices fall into three categories: family-dependent, device-dependent, and design-dependent. The input and output buffer characteristics are common to all SX-A family members. Internal routing delays are device-dependent. Design dependency means actual delays are not determined until after placement and routing of the user's design are complete. The timing characteristics listed in this datasheet represent sample timing numbers of the SX-A devices. Design-specific delay values may be determined by using Timer or performing simulation after successful place-and-route with the Designer software.

Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most timing-critical paths. Critical nets are determined by net property assignment prior to placement and routing. Up to 6 percent of the nets in a design may be designated as critical, while 90 percent of the nets in a design are typical.

Long Tracks

Some nets in the design use long tracks. Long tracks are special routing resources that span multiple rows, columns, or modules. Long tracks employ three to five antifuse connections. This increases capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically, up to 6 percent of nets in a fully utilized device require long tracks. Long tracks contribute approximately 4 ns to 8.4 ns delay. This additional delay is represented statistically in higher fanout routing delays.

Timing Derating

SX-A devices are manufactured with a CMOS process. Therefore, device performance varies according to temperature, voltage, and process changes. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature, and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature, and worst-case processing.

Temperature and Voltage Derating Factors

Table 2-13 • Temperature and Voltage Derating Factors
(Normalized to Worst-Case Commercial, $T_J = 70^\circ\text{C}$, $V_{CCA} = 2.25\text{ V}$)

V_{CCA}	Junction Temperature (T_J)						
	–55°C	–40°C	0°C	25°C	70°C	85°C	125°C
2.250 V	0.79	0.80	0.87	0.89	1.00	1.04	1.14
2.500 V	0.74	0.75	0.82	0.83	0.94	0.97	1.07
2.750 V	0.68	0.69	0.75	0.77	0.87	0.90	0.99

Table 2-17 • **A54SX08A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Networks										
t _{HCKH}	Input Low to High (Pad to R-cell Input)		1.2		1.3		1.5		2.3	ns
t _{HCKL}	Input High to Low (Pad to R-cell Input)		1.0		1.2		1.4		2.0	ns
t _{HPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{HPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{HCKSW}	Maximum Skew		0.4		0.4		0.5		0.8	ns
t _{HP}	Minimum Period	3.2		3.6		4.2		5.8		ns
f _{HMAX}	Maximum Frequency		313		278		238		172	MHz
Routed Array Clock Networks										
t _{RCKH}	Input Low to High (Light Load) (Pad to R-cell Input)		0.9		1.0		1.2		1.7	ns
t _{RCKL}	Input High to Low (Light Load) (Pad to R-cell Input)		1.5		1.7		2.0		2.7	ns
t _{RCKH}	Input Low to High (50% Load) (Pad to R-cell Input)		0.9		1.0		1.2		1.7	ns
t _{RCKL}	Input High to Low (50% Load) (Pad to R-cell Input)		1.5		1.7		2.0		2.7	ns
t _{RCKH}	Input Low to High (100% Load) (Pad to R-cell Input)		1.1		1.3		1.5		2.1	ns
t _{RCKL}	Input High to Low (100% Load) (Pad to R-cell Input)		1.6		1.8		2.1		2.9	ns
t _{RPWH}	Minimum Pulse Width High	1.6		1.8		2.1		2.9		ns
t _{RPWL}	Minimum Pulse Width Low	1.6		1.8		2.1		2.9		ns
t _{RCKSW}	Maximum Skew (Light Load)		0.8		0.9		1.1		1.5	ns
t _{RCKSW}	Maximum Skew (50% Load)		0.8		1.0		1.1		1.5	ns
t _{RCKSW}	Maximum Skew (100% Load)		0.9		1.0		1.2		1.7	ns

Table 2-28 • A54SX32A Timing Characteristics
(Worst-Case Commercial Conditions, $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	-3 Speed ¹		-2 Speed		-1 Speed		Std. Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays ²												
t _{PD}	Internal Array Module	0.8		0.9		1.1		1.2		1.7		ns
Predicted Routing Delays ³												
t _{DC}	FO = 1 Routing Delay, Direct Connect	0.1		0.1		0.1		0.1		0.1		ns
t _{FC}	FO = 1 Routing Delay, Fast Connect	0.3		0.3		0.3		0.4		0.6		ns
t _{RD1}	FO = 1 Routing Delay	0.3		0.3		0.4		0.5		0.6		ns
t _{RD2}	FO = 2 Routing Delay	0.4		0.5		0.5		0.6		0.8		ns
t _{RD3}	FO = 3 Routing Delay	0.5		0.6		0.7		0.8		1.1		ns
t _{RD4}	FO = 4 Routing Delay	0.7		0.8		0.9		1.0		1.4		ns
t _{RD8}	FO = 8 Routing Delay	1.2		1.4		1.5		1.8		2.5		ns
t _{RD12}	FO = 12 Routing Delay	1.7		2.0		2.2		2.6		3.6		ns
R-Cell Timing												
t _{RCO}	Sequential Clock-to-Q	0.6		0.7		0.8		0.9		1.3		ns
t _{CLR}	Asynchronous Clear-to-Q	0.5		0.6		0.6		0.8		1.0		ns
t _{PRESET}	Asynchronous Preset-to-Q	0.6		0.7		0.7		0.9		1.2		ns
t _{SUD}	Flip-Flop Data Input Set-Up	0.6		0.7		0.8		0.9		1.2		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.2		1.4		1.5		1.8		2.5		ns
t _{RECASYN}	Asynchronous Recovery Time	0.3		0.4		0.4		0.5		0.7		ns
t _{HASYN}	Asynchronous Removal Time	0.3		0.3		0.3		0.4		0.6		ns
t _{MPW}	Clock Pulse Width	1.4		1.6		1.8		2.1		2.9		ns
Input Module Propagation Delays												
t _{INYH}	Input Data Pad to Y High 2.5 V LVCMOS	0.6		0.7		0.8		0.9		1.2		ns
t _{INYL}	Input Data Pad to Y Low 2.5 V LVCMOS	1.2		1.3		1.5		1.8		2.5		ns
t _{INYH}	Input Data Pad to Y High 3.3 V PCI	0.5		0.6		0.6		0.7		1.0		ns
t _{INYL}	Input Data Pad to Y Low 3.3 V PCI	0.6		0.7		0.8		0.9		1.3		ns
t _{INYH}	Input Data Pad to Y High 3.3 V LVTTTL	0.8		0.9		1.0		1.2		1.6		ns
t _{INYL}	Input Data Pad to Y Low 3.3 V LVTTTL	1.4		1.6		1.8		2.2		3.0		ns

Notes:

1. All -3 speed grades have been discontinued.
2. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
3. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual performance.

Table 2-40 • A54SX72A Timing Characteristics
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
3.3 V PCI Output Module Timing ²												
t _{DLH}	Data-to-Pad Low to High	2.3		2.7		3.0		3.6		5.0		ns
t _{DHL}	Data-to-Pad High to Low	2.5		2.9		3.2		3.8		5.3		ns
t _{ENZL}	Enable-to-Pad, Z to L	1.4		1.7		1.9		2.2		3.1		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.3		2.7		3.0		3.6		5.0		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.5		2.8		3.2		3.8		5.3		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.5		2.9		3.2		3.8		5.3		ns
d _{TLH} ³	Delta Low to High	0.025		0.03		0.03		0.04		0.045		ns/pF
d _{THL} ³	Delta High to Low	0.015		0.015		0.015		0.015		0.025		ns/pF
3.3 V LVTTTL Output Module Timing ⁴												
t _{DLH}	Data-to-Pad Low to High	3.2		3.7		4.2		5.0		6.9		ns
t _{DHL}	Data-to-Pad High to Low	3.2		3.7		4.2		4.9		6.9		ns
t _{DHLS}	Data-to-Pad High to Low—low slew	10.3		11.9		13.5		15.8		22.2		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.2		2.6		2.9		3.4		4.8		ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew	15.8		18.9		21.3		25.4		34.9		ns
t _{ENZH}	Enable-to-Pad, Z to H	3.2		3.7		4.2		5.0		6.9		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.9		3.3		3.7		4.4		6.2		ns
t _{ENHZ}	Enable-to-Pad, H to Z	3.2		3.7		4.2		4.9		6.9		ns
d _{TLH} ³	Delta Low to High	0.025		0.03		0.03		0.04		0.045		ns/pF
d _{THL} ³	Delta High to Low	0.015		0.015		0.015		0.015		0.025		ns/pF
d _{THLS} ³	Delta High to Low—low slew	0.053		0.053		0.067		0.073		0.107		ns/pF

Notes:

1. All –3 speed grades have been discontinued.
2. Delays based on 10 pF loading and 25 Ω resistance.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[HL|HL|HLS]})$$
 where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[HL|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

Table 2-41 • **A54SX72A Timing Characteristics**
(Worst-Case Commercial Conditions $V_{CCA} = 2.25\text{ V}$, $V_{CCI} = 4.75\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	–3 Speed ¹		–2 Speed		–1 Speed		Std. Speed		–F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
5 V PCI Output Module Timing ²												
t _{DLH}	Data-to-Pad Low to High	2.7		3.1		3.5		4.1		5.7		ns
t _{DHL}	Data-to-Pad High to Low	3.4		3.9		4.4		5.1		7.2		ns
t _{ENZL}	Enable-to-Pad, Z to L	1.3		1.5		1.7		2.0		2.8		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.7		3.1		3.5		4.1		5.7		ns
t _{ENLZ}	Enable-to-Pad, L to Z	3.0		3.5		3.9		4.6		6.4		ns
t _{ENHZ}	Enable-to-Pad, H to Z	3.4		3.9		4.4		5.1		7.2		ns
d _{TLH} ³	Delta Low to High	0.016		0.016		0.02		0.022		0.032		ns/pF
d _{THL} ³	Delta High to Low	0.026		0.03		0.032		0.04		0.052		ns/pF
5 V TTL Output Module Timing ⁴												
t _{DLH}	Data-to-Pad Low to High	2.4		2.8		3.1		3.7		5.1		ns
t _{DHL}	Data-to-Pad High to Low	3.1		3.5		4.0		4.7		6.6		ns
t _{DHLS}	Data-to-Pad High to Low—low slew	7.4		8.5		9.7		11.4		15.9		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.1		2.4		2.7		3.2		4.5		ns
t _{ENZLS}	Enable-to-Pad, Z to L—low slew	7.4		8.4		9.5		11.0		15.4		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.4		2.8		3.1		3.7		5.1		ns
t _{ENLZ}	Enable-to-Pad, L to Z	3.6		4.2		4.7		5.6		7.8		ns
t _{ENHZ}	Enable-to-Pad, H to Z	3.1		3.5		4.0		4.7		6.6		ns
d _{TLH} ³	Delta Low to High	0.014		0.017		0.017		0.023		0.031		ns/pF
d _{THL} ³	Delta High to Low	0.023		0.029		0.031		0.037		0.051		ns/pF
d _{THLS} ³	Delta High to Low—low slew	0.043		0.046		0.057		0.066		0.089		ns/pF

Notes:

1. All –3 speed grades have been discontinued.
2. Delays based on 50 pF loading.
3. To obtain the slew rate, substitute the appropriate Delta value, load capacitance, and the V_{CCI} value into the following equation:

$$\text{Slew Rate [V/ns]} = (0.1 * V_{CCI} - 0.9 * V_{CCI}) / (C_{load} * d_{T[HL|HL|HLS]})$$
 where C_{load} is the load capacitance driven by the I/O in pF
 $d_{T[HL|HL|HLS]}$ is the worst case delta value from the datasheet in ns/pF.
4. Delays based on 35 pF loading.

100-TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	TMS	TMS	TMS
8	V _{CCI}	V _{CCI}	V _{CCI}
9	GND	GND	GND
10	I/O	I/O	I/O
11	I/O	I/O	I/O
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	TRST, I/O	TRST, I/O	TRST, I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	I/O	I/O	I/O
20	V _{CCI}	V _{CCI}	V _{CCI}
21	I/O	I/O	I/O
22	I/O	I/O	I/O
23	I/O	I/O	I/O
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	I/O	I/O	I/O
29	I/O	I/O	I/O
30	I/O	I/O	I/O
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	PRB, I/O	PRB, I/O	PRB, I/O
35	V _{CCA}	V _{CCA}	V _{CCA}

100-TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
36	GND	GND	GND
37	NC	NC	NC
38	I/O	I/O	I/O
39	HCLK	HCLK	HCLK
40	I/O	I/O	I/O
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	V _{CCI}	V _{CCI}	V _{CCI}
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	TDO, I/O	TDO, I/O	TDO, I/O
50	I/O	I/O	I/O
51	GND	GND	GND
52	I/O	I/O	I/O
53	I/O	I/O	I/O
54	I/O	I/O	I/O
55	I/O	I/O	I/O
56	I/O	I/O	I/O
57	V _{CCA}	V _{CCA}	V _{CCA}
58	V _{CCI}	V _{CCI}	V _{CCI}
59	I/O	I/O	I/O
60	I/O	I/O	I/O
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	I/O	I/O	I/O
65	I/O	I/O	I/O
66	I/O	I/O	I/O
67	V _{CCA}	V _{CCA}	V _{CCA}
68	GND	GND	GND
69	GND	GND	GND
70	I/O	I/O	I/O

100-TQFP			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
71	I/O	I/O	I/O
72	I/O	I/O	I/O
73	I/O	I/O	I/O
74	I/O	I/O	I/O
75	I/O	I/O	I/O
76	I/O	I/O	I/O
77	I/O	I/O	I/O
78	I/O	I/O	I/O
79	I/O	I/O	I/O
80	I/O	I/O	I/O
81	I/O	I/O	I/O
82	V _{CCI}	V _{CCI}	V _{CCI}
83	I/O	I/O	I/O
84	I/O	I/O	I/O
85	I/O	I/O	I/O
86	I/O	I/O	I/O
87	CLKA	CLKA	CLKA
88	CLKB	CLKB	CLKB
89	NC	NC	NC
90	V _{CCA}	V _{CCA}	V _{CCA}
91	GND	GND	GND
92	PRA, I/O	PRA, I/O	PRA, I/O
93	I/O	I/O	I/O
94	I/O	I/O	I/O
95	I/O	I/O	I/O
96	I/O	I/O	I/O
97	I/O	I/O	I/O
98	I/O	I/O	I/O
99	I/O	I/O	I/O
100	TCK, I/O	TCK, I/O	TCK, I/O

329-Pin PBGA		329-Pin PBGA		329-Pin PBGA		329-Pin PBGA	
Pin Number	A54SX32A Function	Pin Number	A54SX32A Function	Pin Number	A54SX32A Function	Pin Number	A54SX32A Function
A1	GND	AA15	I/O	AC6	I/O	B20	I/O
A2	GND	AA16	I/O	AC7	I/O	B21	I/O
A3	V _{CCI}	AA17	I/O	AC8	I/O	B22	GND
A4	NC	AA18	I/O	AC9	V _{CCI}	B23	V _{CCI}
A5	I/O	AA19	I/O	AC10	I/O	C1	NC
A6	I/O	AA20	TDO, I/O	AC11	I/O	C2	TDI, I/O
A7	V _{CCI}	AA21	V _{CCI}	AC12	I/O	C3	GND
A8	NC	AA22	I/O	AC13	I/O	C4	I/O
A9	I/O	AA23	V _{CCI}	AC14	I/O	C5	I/O
A10	I/O	AB1	I/O	AC15	NC	C6	I/O
A11	I/O	AB2	GND	AC16	I/O	C7	I/O
A12	I/O	AB3	I/O	AC17	I/O	C8	I/O
A13	CLKB	AB4	I/O	AC18	I/O	C9	I/O
A14	I/O	AB5	I/O	AC19	I/O	C10	I/O
A15	I/O	AB6	I/O	AC20	I/O	C11	I/O
A16	I/O	AB7	I/O	AC21	NC	C12	I/O
A17	I/O	AB8	I/O	AC22	V _{CCI}	C13	I/O
A18	I/O	AB9	I/O	AC23	GND	C14	I/O
A19	I/O	AB10	I/O	B1	V _{CCI}	C15	I/O
A20	I/O	AB11	PRB, I/O	B2	GND	C16	I/O
A21	NC	AB12	I/O	B3	I/O	C17	I/O
A22	V _{CCI}	AB13	HCLK	B4	I/O	C18	I/O
A23	GND	AB14	I/O	B5	I/O	C19	I/O
AA1	V _{CCI}	AB15	I/O	B6	I/O	C20	I/O
AA2	I/O	AB16	I/O	B7	I/O	C21	V _{CCI}
AA3	GND	AB17	I/O	B8	I/O	C22	GND
AA4	I/O	AB18	I/O	B9	I/O	C23	NC
AA5	I/O	AB19	I/O	B10	I/O	D1	I/O
AA6	I/O	AB20	I/O	B11	I/O	D2	I/O
AA7	I/O	AB21	I/O	B12	PRA, I/O	D3	I/O
AA8	I/O	AB22	GND	B13	CLKA	D4	TCK, I/O
AA9	I/O	AB23	I/O	B14	I/O	D5	I/O
AA10	I/O	AC1	GND	B15	I/O	D6	I/O
AA11	I/O	AC2	V _{CCI}	B16	I/O	D7	I/O
AA12	I/O	AC3	NC	B17	I/O	D8	I/O
AA13	I/O	AC4	I/O	B18	I/O	D9	I/O
AA14	I/O	AC5	I/O	B19	I/O	D10	I/O

144-Pin FBGA			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
A1	I/O	I/O	I/O
A2	I/O	I/O	I/O
A3	I/O	I/O	I/O
A4	I/O	I/O	I/O
A5	V _{CCA}	V _{CCA}	V _{CCA}
A6	GND	GND	GND
A7	CLKA	CLKA	CLKA
A8	I/O	I/O	I/O
A9	I/O	I/O	I/O
A10	I/O	I/O	I/O
A11	I/O	I/O	I/O
A12	I/O	I/O	I/O
B1	I/O	I/O	I/O
B2	GND	GND	GND
B3	I/O	I/O	I/O
B4	I/O	I/O	I/O
B5	I/O	I/O	I/O
B6	I/O	I/O	I/O
B7	CLKB	CLKB	CLKB
B8	I/O	I/O	I/O
B9	I/O	I/O	I/O
B10	I/O	I/O	I/O
B11	GND	GND	GND
B12	I/O	I/O	I/O
C1	I/O	I/O	I/O
C2	I/O	I/O	I/O
C3	TCK, I/O	TCK, I/O	TCK, I/O
C4	I/O	I/O	I/O
C5	I/O	I/O	I/O
C6	PRA, I/O	PRA, I/O	PRA, I/O
C7	I/O	I/O	I/O
C8	I/O	I/O	I/O
C9	I/O	I/O	I/O
C10	I/O	I/O	I/O
C11	I/O	I/O	I/O
C12	I/O	I/O	I/O

144-Pin FBGA			
Pin Number	A54SX08A Function	A54SX16A Function	A54SX32A Function
D1	I/O	I/O	I/O
D2	V _{CCI}	V _{CCI}	V _{CCI}
D3	TDI, I/O	TDI, I/O	TDI, I/O
D4	I/O	I/O	I/O
D5	I/O	I/O	I/O
D6	I/O	I/O	I/O
D7	I/O	I/O	I/O
D8	I/O	I/O	I/O
D9	I/O	I/O	I/O
D10	I/O	I/O	I/O
D11	I/O	I/O	I/O
D12	I/O	I/O	I/O
E1	I/O	I/O	I/O
E2	I/O	I/O	I/O
E3	I/O	I/O	I/O
E4	I/O	I/O	I/O
E5	TMS	TMS	TMS
E6	V _{CCI}	V _{CCI}	V _{CCI}
E7	V _{CCI}	V _{CCI}	V _{CCI}
E8	V _{CCI}	V _{CCI}	V _{CCI}
E9	V _{CCA}	V _{CCA}	V _{CCA}
E10	I/O	I/O	I/O
E11	GND	GND	GND
E12	I/O	I/O	I/O
F1	I/O	I/O	I/O
F2	I/O	I/O	I/O
F3	NC	NC	NC
F4	I/O	I/O	I/O
F5	GND	GND	GND
F6	GND	GND	GND
F7	GND	GND	GND
F8	V _{CCI}	V _{CCI}	V _{CCI}
F9	I/O	I/O	I/O
F10	GND	GND	GND
F11	I/O	I/O	I/O
F12	I/O	I/O	I/O

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
K5	I/O	I/O	I/O
K6	V _{CCI}	V _{CCI}	V _{CCI}
K7	GND	GND	GND
K8	GND	GND	GND
K9	GND	GND	GND
K10	GND	GND	GND
K11	V _{CCI}	V _{CCI}	V _{CCI}
K12	I/O	I/O	I/O
K13	I/O	I/O	I/O
K14	I/O	I/O	I/O
K15	NC	I/O	I/O
K16	I/O	I/O	I/O
L1	I/O	I/O	I/O
L2	I/O	I/O	I/O
L3	I/O	I/O	I/O
L4	I/O	I/O	I/O
L5	I/O	I/O	I/O
L6	I/O	I/O	I/O
L7	V _{CCI}	V _{CCI}	V _{CCI}
L8	V _{CCI}	V _{CCI}	V _{CCI}
L9	V _{CCI}	V _{CCI}	V _{CCI}
L10	V _{CCI}	V _{CCI}	V _{CCI}
L11	I/O	I/O	I/O
L12	I/O	I/O	I/O
L13	I/O	I/O	I/O
L14	I/O	I/O	I/O
L15	I/O	I/O	I/O
L16	NC	I/O	I/O
M1	I/O	I/O	I/O
M2	I/O	I/O	I/O
M3	I/O	I/O	I/O
M4	I/O	I/O	I/O
M5	I/O	I/O	I/O
M6	I/O	I/O	I/O
M7	I/O	I/O	QCLKA
M8	PRB, I/O	PRB, I/O	PRB, I/O
M9	I/O	I/O	I/O

256-Pin FBGA			
Pin Number	A54SX16A Function	A54SX32A Function	A54SX72A Function
M10	I/O	I/O	I/O
M11	I/O	I/O	I/O
M12	NC	I/O	I/O
M13	I/O	I/O	I/O
M14	NC	I/O	I/O
M15	I/O	I/O	I/O
M16	I/O	I/O	I/O
N1	I/O	I/O	I/O
N2	I/O	I/O	I/O
N3	I/O	I/O	I/O
N4	I/O	I/O	I/O
N5	I/O	I/O	I/O
N6	I/O	I/O	I/O
N7	I/O	I/O	I/O
N8	I/O	I/O	I/O
N9	I/O	I/O	I/O
N10	I/O	I/O	I/O
N11	I/O	I/O	I/O
N12	I/O	I/O	I/O
N13	I/O	I/O	I/O
N14	I/O	I/O	I/O
N15	I/O	I/O	I/O
N16	I/O	I/O	I/O
P1	I/O	I/O	I/O
P2	GND	GND	GND
P3	I/O	I/O	I/O
P4	I/O	I/O	I/O
P5	NC	I/O	I/O
P6	I/O	I/O	I/O
P7	I/O	I/O	I/O
P8	I/O	I/O	I/O
P9	I/O	I/O	I/O
P10	NC	I/O	I/O
P11	I/O	I/O	I/O
P12	I/O	I/O	I/O
P13	V _{CCA}	V _{CCA}	V _{CCA}
P14	I/O	I/O	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
C19	I/O	I/O
C20	V _{CCI}	V _{CCI}
C21	I/O	I/O
C22	I/O	I/O
C23	I/O	I/O
C24	I/O	I/O
C25	NC*	I/O
C26	NC*	I/O
D1	NC*	I/O
D2	TMS	TMS
D3	I/O	I/O
D4	V _{CCI}	V _{CCI}
D5	NC*	I/O
D6	TCK, I/O	TCK, I/O
D7	I/O	I/O
D8	I/O	I/O
D9	I/O	I/O
D10	I/O	I/O
D11	I/O	I/O
D12	I/O	QCLKC
D13	I/O	I/O
D14	I/O	I/O
D15	I/O	I/O
D16	I/O	I/O
D17	I/O	I/O
D18	I/O	I/O
D19	I/O	I/O
D20	I/O	I/O
D21	V _{CCI}	V _{CCI}
D22	GND	GND
D23	I/O	I/O
D24	I/O	I/O
D25	NC*	I/O
D26	NC*	I/O
E1	NC*	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
E2	NC*	I/O
E3	I/O	I/O
E4	I/O	I/O
E5	GND	GND
E6	TDI, IO	TDI, IO
E7	I/O	I/O
E8	I/O	I/O
E9	I/O	I/O
E10	I/O	I/O
E11	I/O	I/O
E12	I/O	I/O
E13	V _{CCA}	V _{CCA}
E14	CLKB	CLKB
E15	I/O	I/O
E16	I/O	I/O
E17	I/O	I/O
E18	I/O	I/O
E19	I/O	I/O
E20	I/O	I/O
E21	I/O	I/O
E22	I/O	I/O
E23	I/O	I/O
E24	I/O	I/O
E25	V _{CCI}	V _{CCI}
E26	GND	GND
F1	V _{CCI}	V _{CCI}
F2	NC*	I/O
F3	NC*	I/O
F4	I/O	I/O
F5	I/O	I/O
F22	I/O	I/O
F23	I/O	I/O
F24	I/O	I/O
F25	I/O	I/O
F26	NC*	I/O

484-Pin FBGA		
Pin Number	A54SX32A Function	A54SX72A Function
G1	NC*	I/O
G2	NC*	I/O
G3	NC*	I/O
G4	I/O	I/O
G5	I/O	I/O
G22	I/O	I/O
G23	V _{CCA}	V _{CCA}
G24	I/O	I/O
G25	NC*	I/O
G26	NC*	I/O
H1	NC*	I/O
H2	NC*	I/O
H3	I/O	I/O
H4	I/O	I/O
H5	I/O	I/O
H22	I/O	I/O
H23	I/O	I/O
H24	I/O	I/O
H25	NC*	I/O
H26	NC*	I/O
J1	NC*	I/O
J2	NC*	I/O
J3	I/O	I/O
J4	I/O	I/O
J5	I/O	I/O
J22	I/O	I/O
J23	I/O	I/O
J24	I/O	I/O
J25	V _{CCI}	V _{CCI}
J26	NC*	I/O
K1	I/O	I/O
K2	V _{CCI}	V _{CCI}
K3	I/O	I/O
K4	I/O	I/O
K5	V _{CCA}	V _{CCA}

Note: *These pins must be left floating on the A54SX32A device.

Previous Version	Changes in Current Version (v5.3)	Page
v4.0 (continued)	Table 2-12 was updated.	2-11
	The was updated.	2-14
	The "Sample Path Calculations" were updated.	2-14
	Table 2-13 was updated.	2-17
	Table 2-13 was updated.	2-17
	All timing tables were updated.	2-18 to 2-52
v3.0	The "Actel Secure Programming Technology with FuseLock™ Prevents Reverse Engineering and Design Theft" section was updated.	1-i
	The "Ordering Information" section was updated.	1-ii
	The "Temperature Grade Offering" section was updated.	1-iii
	The Figure 1-1 • SX-A Family Interconnect Elements was updated.	1-1
	The "Clock Resources" section was updated.	1-5
	The Table 1-1 • SX-A Clock Resources is new.	1-5
	The "User Security" section is new.	1-7
	The "I/O Modules" section was updated.	1-7
	The Table 1-2 • I/O Features was updated.	1-8
	The Table 1-3 • I/O Characteristics for All I/O Configurations is new.	1-8
	The Table 1-4 • Power-Up Time at which I/Os Become Active is new.	1-8
	The Figure 1-12 • Device Selection Wizard is new.	1-9
	The "Boundary-Scan Pin Configurations and Functions" section is new.	1-9
	The Table 1-9 • Device Configuration Options for Probe Capability (TRST Pin Reserved) is new.	1-11
	The "SX-A Probe Circuit Control Pins" section was updated.	1-12
	The "Design Considerations" section was updated.	1-12
	The Figure 1-13 • Probe Setup was updated.	1-12
	The Design Environment was updated.	1-13
	The Figure 1-13 • Design Flow is new.	1-11
	The "Absolute Maximum Ratings*" section was updated.	1-12
	The "Recommended Operating Conditions" section was updated.	1-12
	The "Electrical Specifications" section was updated.	1-12
	The "2.5V LVCMOS2 Electrical Specifications" section was updated.	1-13
	The "SX-A Timing Model" and "Sample Path Calculations" equations were updated.	1-23
	The "Pin Description" section was updated.	1-15
v2.0.1	The "Design Environment" section has been updated.	1-13
	The "I/O Modules" section, and Table 1-2 • I/O Features have been updated.	1-8
	The "SX-A Timing Model" section and the "Timing Characteristics" section have new timing numbers.	1-23